

Test Photographs
Immedia Semiconductor, LLC
FCC ID: 2AF77- H2111705



Retlif Testing Laboratories

Results No. R-6584H-3

**Test Photographs
Occupied Bandwidth (6dB Bandwidth)**



EUT Configuration



Retlif Testing Laboratories

Results No. R-6584H-3

**Test Photographs
Conducted Emissions, Power Output**



EUT Configuration



Retlif Testing Laboratories

Results No. R-6584H-3

Test Photographs
Antenna Port, Conducted Emissions



EUT Configuration




Retlif Testing Laboratories

Results No. R-6584H-3

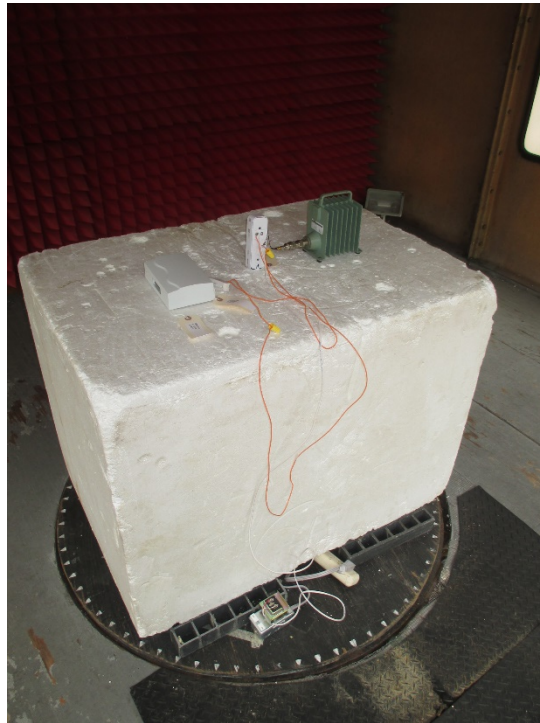
Test Photographs
Antenna Port, Power Density




EUT Configuration

	Retlif Testing Laboratories
	Results No. R-6584H-3

Test Photographs
Spurious Radiated Emissions, 30 MHz to 25 GHz



EUT Configuration

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	Results No. R-6584H-3

Test Photographs
Spurious Radiated Emissions, 30 MHz to 25 GHz



Horizontal Polarization, 30 to 200 MHz



Vertical Polarization, 30 to 200 MHz



Retlif Testing Laboratories

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Test Photographs
Spurious Radiated Emissions, 30 MHz to 25 GHz



Horizontal Polarization, 200 MHz to 1 GHz



Vertical Polarization, 200 MHz to 1 GHz



Retlif Testing Laboratories

Results No. R-6584H-3

Test Photographs
Spurious Radiated Emissions, 30 MHz to 25 GHz



Horizontal Polarization, 1 to 18 GHz



Vertical Polarization, 1 to 18 GHz



Retlif Testing Laboratories

Results No. R-6584H-3

Test Photographs
Spurious Radiated Emissions, 30 MHz to 25 GHz



Horizontal Polarization, 18 to 25 GHz



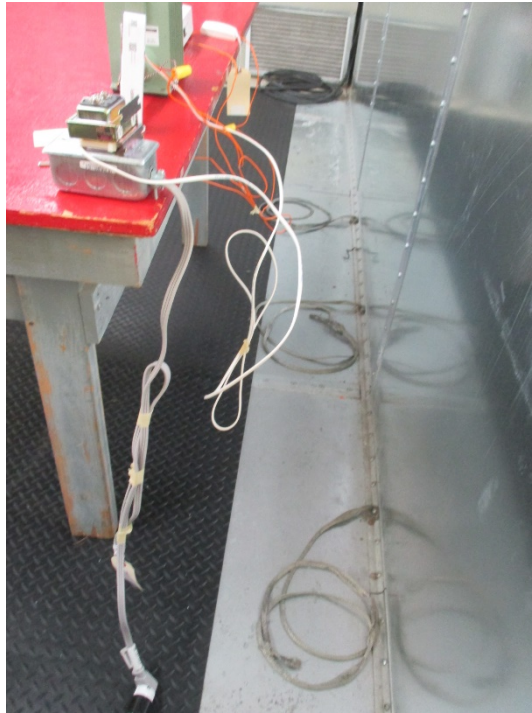
Vertical Polarization, 18 to 25 GHz



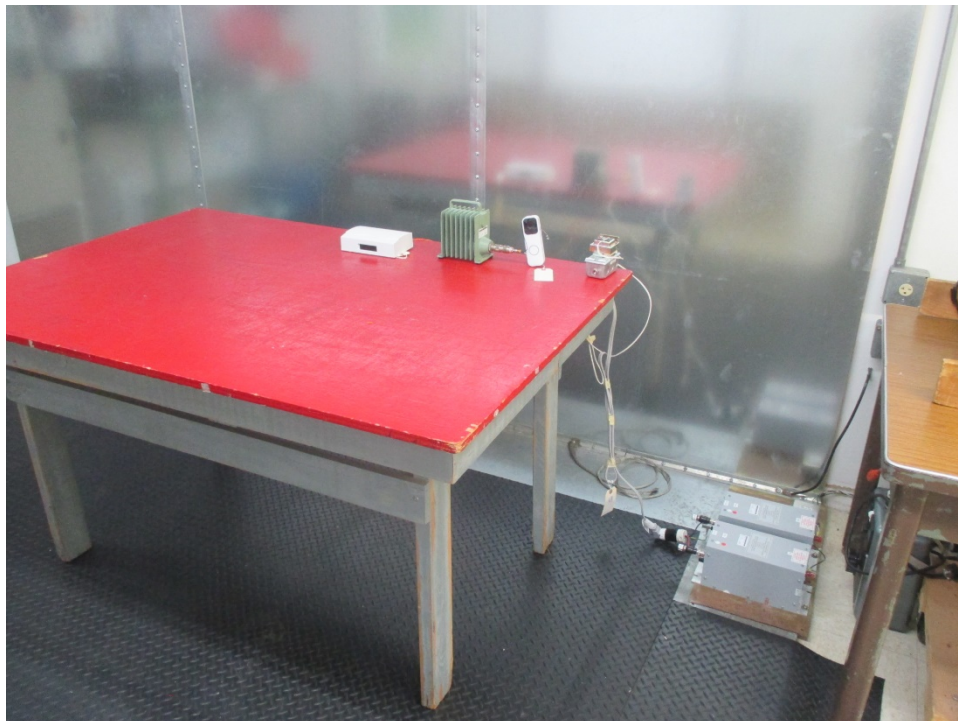
Retlif Testing Laboratories

Results No. R-6584H-3

Test Photographs
Conducted Emissions, Power Leads, 150 kHz to 30 MHz



EUT Configuration



Test Setup



Retlif Testing Laboratories

Results No. R-6584H-3

**Test Photographs
Duty Cycle**



Test Setup



Retlif Testing Laboratories

Results No. R-6584H-3